	Se	arcn	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/716,870	KAWATO ET AL.	
Examiner ·	Art Unit	
Alex Liew	2624	

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Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner
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SEARCH N (INCLUDING SEARC)
	DATE	EXMR
382/118 limited to text search	6/3/2007	AL
382/118 crossed with 382/154	6/7/2007	AL
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